

# PHYSICS 108: Electronics Super-Summary

Jean-Michel Borit

May 2024

In these notes, I provide an overview of the parameters we should use for our measurements. As far as the electronics are concerned, there are two key instruments we need to control: the lock-in amplifier (used for voltage readouts, from which we can determine  $\rho$ ) and the sourcemeter (provides the input current). These two have several knobs we can tune, which is why we should do our best effort to constrain our parameter space appropriately.

## 1 Sourcemeter

The lock-in parameters are mostly contingent upon the source current. Thus, we take a look at the latter first. The current has two characteristics we will be interested in controlling:

1. the source amplitude
2. the source frequency.

### 1.1 Source Amplitude

The maximal current we can run in the experiment will be likely determined by heating considerations. Consider an upper bound for the power in the circuit,  $P_{\max}$ , which is set by the heating rate of the experimental setup. It is straightforward to see that, to stay below threshold under a fixed resistance  $R$ , the current must satisfy

$$I < \sqrt{\frac{P_{\max}}{R}}.$$

Recalling that  $R = \rho L/A$ , we rewrite Eq. 1.1 as

$$I < \sqrt{\frac{AP_{\max}}{\rho L}}. \tag{1}$$

Here,  $A$  is the cross-sectional area of the structure we measure (nanowires) and  $L$  is the length over which the current propagates. Based on literature, we estimate that  $\rho$  will take values in the order of  $\mu\Omega\cdot\text{cm}$ . Similarly, we expect  $A$

to in the order of  $\pi \cdot 25 \text{ nm}^2$ , and  $L$  to be in the order of  $2 \text{ }\mu\text{m}$ . With these numbers, based on Eq. 1, we obtain the condition

$$I < I_{\max} \sim 0.01 \text{ A.} \quad (2)$$

The above result reduces to  $0.001 \text{ A}$  for resistivities in the order of  $\text{m}\Omega\cdot\text{cm}$ . Another relevant consideration to keep in mind is sensitivity. This will set the lower-bound of the currents we should send. As previously mentioned, we expect to measure resistivities in the order of  $\mu\Omega\cdot\text{cm}$ . As earlier, this means we should expect a resistance of  $R \sim 10 \text{ }\Omega$  ( $10\text{K }\Omega$  for resistivities in the order of  $\text{m}\Omega\cdot\text{cm}$ ). Our lock-in amplifiers have a maximum sensitivity in the order nV's. From the textbook expression  $V = IR$ , we know that, if we want measurements with variations exceeding the  $1 \text{ nV}$  threshold, we must require

$$I > I_{\min} = \frac{\Delta V_{\min}}{R}. \quad (3)$$

This fully constraints the operational regime of currents we can work with. In particular, we should make sure to enforce

$$I_{\min} < I < I_{\max} \Rightarrow 10^{-11} < I < 0.01 \text{ (0.001) A.} \quad (4)$$

## 1.2 Source Frequency

The source frequency might be a bit trickier to determine. Based on conversations with Sandesh, heuristically, we need to stay around  $\sim 100 \text{ Hz}$  in order to prevent the undesired effects of parasitic capacitance. Thus, we set

$$\omega_{\text{src}} = 100 \text{ Hz.} \quad (5)$$

## 2 Lock-In Amplifier

The lock-in amplifier has three critical nobs. These are:

1. the amplitude of the reference signal
2. the frequency of the reference signal
3. the integration constant
4. the sensitivity.

### 2.1 Reference Amplitude

Uncertain as to how to determine this one. I think the only consideration is to avoid heating things up.

## 2.2 Reference Frequency

To the best of my understanding, we want this frequency to be equal to that of our source signal. This is no problem, for we can control the source frequency experimentally. Thus, the only relevant constraint to be considered here is

$$\omega_{\text{ref}} = \omega_{\text{src}}. \quad (6)$$

## 2.3 The Integration Constant

For reliable readings, we need this constant to be larger than a full oscillation cycle in the lock-in. Thus, we need to enforce

$$\tau_C > 1/\omega_{\text{ref}} = 1/\omega_{\text{src}}. \quad (7)$$

Note that we can't simply make  $\tau_C$  as large as possible for better accuracy, for doing so would make our measurements exceedingly long. The lock-in provides a limited number of integration constant options. Thus, amongst the ones that satisfy  $\tau_C > 1/\omega_{\text{ref}}$ , we should pick the smallest. Lastly, when implementing a sweeping routine, we need to make sure that our wait times between each reading allow for enough time for the device to cool down –and for  $\tau_C$  to pass.

## 2.4 Sensitivity

This variable is fully determined by  $\Delta V_{\text{min}}$  –or whatever sensitivity we would like to enforce.